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Visokotokovne preskusne tehnike - Definicije in zahteve za preskusne toke in merilne sisteme

High-current test techniques - Definitions and requirements for test currents and measuring systems

Hochstrom-Prüftechnik - Begriffe und Anforderungen für Hochstrom-Messungen

Techniques des essais à haute intensité - Définitions et exigences relatives aux courants d'essai et systèmes de mesure

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EUROPEAN STANDARD

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High-current test techniques - Definitions and requirements for test currents and measuring systems (IEC 62475:2026)

Techniques des essais à haute intensité - Définitions et exigences relatives aux courants d'essai et systèmes de mesure
(IEC 62475:2026)

Hochstrom-Prüftechnik - Begriffe und Anforderungen für Hochstrom-Messungen
(IEC 62475:2026)

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European foreword

The text of document 42/472/FDIS, future edition 2 of IEC 62475, prepared by TC 42 "High-voltage and high-current test techniques" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62475:2026.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2027-09-30
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IEC 60051-2:2018	NOTE	Approved as EN IEC 60051-2:2021 (not modified)
IEC 60060-1:2025	NOTE	Approved as EN IEC 60060-1:2025 (not modified)
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IEC 60099-4:2014	NOTE	Approved as EN 60099-4:2014 (not modified)
IEC 60099-4:2014	NOTE	Approved as EN 60099-4:2014 (not modified)
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Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

Publication	Year	Title	EN/HD	Year
ISO/IEC Guide 98-3	2008	Uncertainty of measurement - Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)	-	-

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High-current test techniques - Definitions and requirements for test currents and measuring systems

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IEC 62475 has been prepared by IEC technical committee 42: High-voltage and high-current test techniques. It is an International Standard.

This second edition cancels and replaces the first edition published in 2010. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) minor errors in edition 1 have corrected;
b) terms and definitions have been modified to achieve best possible adherence to IEC 60060-2:2025 and have been ascribed appropriate [SOURCE];
c) terms and definitions which in edition 1 were presented in clauses other than Clause 3 have been moved into Clause 3.

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d) Annex B, Clause B.4 has been amended to provide an example of uncertainty calculation for the use of an approved measuring system;

e) Clause C.2 has been deleted since the definitions given there are not referred to, with the exception of the origin of the step, which is used in Annex D. The applicable information has been added to Annex D as Note 1.

f) Annex G, Clause G.8 has been amended to replace “peak factor” by “a factor”. Texts have been clarified. Equations for relation between factor κ and cos ϕ have been developed to a simplified form.

g) Annex G, Clause G.9 has been added.

The text of this International Standard is based on the following documents:

Draft	Report on voting
42/472/FDIS	42/475/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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